

03500.017636.

PATENT APPLICATION

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE



In re Application of:

SHUNICHI ISHIHARA, et al.

Application No.: 10/530,189

Filed: October 10, 2003

For: POLYCRYSTALLINE SILICON
SUBSTRATE

May 5, 2006

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT

Sir:

In compliance with the duty of disclosure under 37 C.F.R. § 1.56 and in accordance with the practice under 37 C.F.R. §§ 1.97 and 1.98, the Examiner's attention is directed to the documents listed on the enclosed Form PTO-1449. Copies of the listed documents, other than U.S. patent documents, are enclosed.

The following documents are discussed at the following pages of the specification:

<u>Documents</u>	<u>Page(s)</u>
Haruo Itoh, et al., Journal of Crystal Growth	3
T. H. Wang, et al., Solar Energy Materials and Solar Cells	4-5

The Examiner's attention is also directed to the following U.S.

Applications:

<u>Application No.</u>	<u>Filing Date</u>	<u>Applicant(s)</u>
10/549,600	03/24/2004	S. Ishihara
10/563,115	05/17/2005	M. Mizutani S. Nishida K. Nakagawa
10/976,853	11/01/2004	T. Yoshino S. Nishida

This Information Disclosure Statement is being filed before the issuance of a first Office Action on the merits. Therefore, no fee under 37 C.F.R. § 1.97(c)(2) is believed due. Nevertheless, the Commissioner may charge Deposit Account No. 06-1205, should any fee be due for filing this paper.

Applicants request that the above information be considered by the Examiner and that a copy of the enclosed Form PTO-1449 be initialed and returned indicating that such information has been considered.

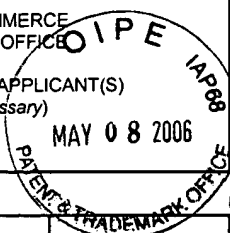
Applicants' undersigned attorney may be reached in our Costa Mesa,
California office at (714) 540-8700. All correspondence should continue to be directed to
our below-listed address.

Respectfully submitted,

A handwritten signature in black ink, appearing to read 'D. Vadnais', is written over a horizontal line.

Damond E. Vadnais
Attorney for Applicants
Registration No.: 52,310

FITZPATRICK, CELLA, HARPER & SCINTO
30 Rockefeller Plaza
New York, New York 10112-3800
Facsimile: (212) 218-2200

FORM PTO 1449 (modified) U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary)			ATTY DOCKET NO. 03500.017636.		APPLICATION NO. 10/530,189		
			APPLICANT SHUNICHI ISHIHARA, et al.				
			FILING DATE October 10, 2003			GROUP	
U.S. PATENT DOCUMENTS							
*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
		6,953,506	10/11/05	Iwane, et al.	117	206	
		6,869,863	03/22/05	Nishida	438	497	
		6,824,609	11/30/04	Saito, et al.	117	54	
		6,818,911	11/16/04	Tamamori, et al.	250	492.22	
		6,818,104	11/16/04	Iwasaki, et al.	204	199	
		6,802,926	10/12/04	Mizutani, et al.	156	247	
		6,802,900	10/12/04	Iwane, et al.	117	54	
		6,756,289	06/29/04	Nakagawa, et al.	438	478	
		6,682,990	01/27/04	Iwane, et al.	438	458	
		6,664,169	12/16/03	Iwasaki, et al.	438	409	
		6,653,554	11/25/03	Ishihara	136	258	
		6,566,277	05/20/03	Nakagawa, et al.	438	761	
		6,566,235	05/20/03	Nishida, et al.	438	458	
		6,515,218	02/04/03	Shimizu, et al.	136	256	
		6,500,731	12/31/02	Nakagawa, et al.	438	455	
FOREIGN PATENT DOCUMENTS							
		DOCUMENT- NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT
OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)							
		Haruo Itoh, et al., "Characterization of Silicon Layers Epitaxially Grown on Metallurgical-Grade Polycrystalline Substrates", Journal of Crystal Growth 45 (1978), pp. 446-453.					
		T. H. Wang, et al., "Growth of silicon thin layers on cast MG-Si from metal solutions for solar cells", Solar Energy Materials and Solar Cells 41/42 (1996), pp. 19-30.					
EXAMINER				DATE CONSIDERED			

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

FORM PTO 1449 (modified) U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE LIST OF REFERENCES CITED BY APPLICANT(S) <i>(Use several sheets if necessary)</i>				ATTY DOCKET NO. 03500.017636.		APPLICATION NO. 10/530,189	
				APPLICANT SHUNICHI ISHIHARA, et al.			
				FILING DATE October 10, 2003		GROUP	
U.S. PATENT DOCUMENTS							
*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
		6,464,762	10/15/02	Arao	106	1.22	
		6,452,091	09/17/02	Nakagawa, et al.	136	261	
		6,429,035	08/06/02	Nakagawa, et al.	438	57	
		6,391,743	05/21/02	Iwane, et al.	438	458	
		6,387,780	05/14/02	Nishida, et al.	438	497	
		6,384,313	05/07/02	Nakagawa, et al.	136	244	
		6,331,208	12/18/01	Nishida, et al.	117	89	
		6,271,462	08/07/01	Tsuzuki, et al.	136	290	
		6,265,242	07/24/01	Komori, et al.	438	66	
		6,258,698	07/10/01	Iwasaki, et al.	438	455	
		6,258,666	07/10/01	Mizutani, et al.	438	258	
		6,248,948	06/19/01	Nakagawa, et al.	136	244	
		6,211,038	04/03/01	Nakagawa, et al.	438	409	
		6,190,937	02/20/01	Nakagawa, et al.	438	67	
		6,184,458	02/06/01	Murakami, et al.	136	256	
		6,180,868	01/30/01	Yoshino, et al.	136	244	
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT
OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)							
EXAMINER				DATE CONSIDERED			

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Sheet 2 of 3

FORM PTO 1449 (modified) U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary)				ATTY DOCKET NO. 03500.017636.		APPLICATION NO. 10/530,189	
				APPLICANT SHUNICHI ISHIHARA, et al.			
				FILING DATE October 10, 2003		GROUP	

U.S. PATENT DOCUMENTS							
*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
		6,172,296	01/09/01	Iwasaki, et al.	136	256	
		6,162,986	12/19/00	Shiotsuka, et al.	136	244	
		6,140,209	10/31/00	Iwane, et al.	438	458	
		6,110,347	08/29/00	Arao, et al.	205	333	
		5,986,204	11/16/99	Iwasaki, et al.	136	256	
		5,981,864	11/09/99	Mizutani, et al.	136	244	
		5,770,463	06/23/98	Nakagawa, et al.	437	2	
		5,714,010	02/03/98	Matsuyama, et al.	118	723	
		5,712,199	01/27/98	Nakagawa, et al.	438	62	
		5,510,151	04/23/96	Matsuyama, et al.	427	509	
		5,486,238	01/23/96	Nakagawa, et al.	136	259	
		2005/0136576	06/23/05	Ishihara, et al.	438	162	
		2005/0109388	05/26/05	Murakami, et al.	136	255	
		2005/0087226	04/28/05	Nishida, et al.	136	256	
		2005/0066881	03/31/05	Nakagawa, et al.	117	18	
		2004/0118337	06/24/04	Mizutani, et al.	117	54	
		2004/0065251	04/08/04	Nishida, et al.	117	54	
		2002/0092464	07/18/02	Nakagawa, et al.	117	94	

FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT

OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)		

EXAMINER	DATE CONSIDERED
----------	-----------------

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Sheet 3 of 3